Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/628,228	TAKENAKA, HIDEKI	
Examiner	Art Unit	
Aley Liew	2624	

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Class	Subclass	Date	Examiner
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INT	ERFERENC	E SEARCH	IED
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
382/118 (limited to text search)	10/5/2006	AL	
382/118 limited to text search	2/7/2007	AL	
382/115,116,118 limited to text search	7/19/2007	AL	
382/115,116,118 limited to text search	12/22/2007	AL	